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The GreenMOS® high voltage MOSFET utilizes charge balance technology to achieve outstanding low on-resistance and lower gate charge. It is engineered to minimize conduction loss, provide superior switching performance and robust avalanche capability.

The GreenMOS® Generic series is optimized for extreme switching performance to minimize switching loss. It is tailored for high power density applications to meet the highest efficiency standards.

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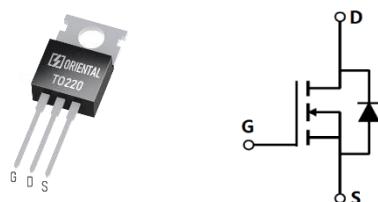
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Parameter	Value	Unit
V _{DS, min} @ T _{j(max)}	700	V
I _{D, pulse}	75	A
R _{DS(ON), max} @ V _{GS} =10V	125	P
Q _g	41.9	nC

9 MWJS5R YMU

Product Name	Package	Marking
OSG65R125PF	TO220	OSG65R125P

MOMIS U 5 R YMU



Absolute Maximum Ratings at $T_j=25\text{ }^\circ\text{C}$ &unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	650	V
Gate-source voltage	V_{GS}	± 30	V
Continuous drain current ¹⁾ , $T_C=25\text{ }^\circ\text{C}$	I_D	25	A
Continuous drain current ¹⁾ , $T_C=100\text{ }^\circ\text{C}$		16	
Pulsed drain current ²⁾ , $T_C=25\text{ }^\circ\text{C}$	$I_{D,\text{pulse}}$	75	A
Continuous diode forward current ¹⁾ , $T_C=25\text{ }^\circ\text{C}$	I_S	25	A
Diode pulsed current ²⁾ , $T_C=25\text{ }^\circ\text{C}$	$I_{S,\text{pulse}}$	75	A
Power dissipation ³⁾ , $T_C=25\text{ }^\circ\text{C}$	P_D	219	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	730	mJ
MOSFET dv/dt ruggedness, $V_{DS} \ll 9$	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS} \ll 9_{SD}, \text{ "p}$	dv/dt	15	V/ns
Operation and storage temperature	T_{stg}, T_j	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	$R_{\text{th},\text{JC}}$	0.57	$^\circ\text{C}/\text{W}$
Thermal resistance, junction-ambient ⁴⁾	$R_{\text{th},\text{JA}}$	62	$^\circ\text{C}/\text{W}$

Electrical Characteristics at $T_j=25\text{ }^\circ\text{C}$ &unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DS}	650			V	$V_{GS}=0\text{ V}, I_D=1\text{ mA}$
		700	740			$V_{GS}=0\text{ V}, I_D=1\text{ mA}, T_j=150\text{ }^\circ\text{C}$
Gate threshold voltage	$V_{GS(\text{th})}$	2.9		3.9	V	$V_{DS}=V_{GS}, I_D=1\text{ mA}$
Drain-source on-state resistance	$R_{DS(\text{ON})}$		0.115	0.125		$V_{GS}=10\text{ V}, I_D=12.5\text{ A}$
			0.278			$V_{GS}=10\text{ V}, I_D=12.5\text{ A}, T_j=150\text{ }^\circ\text{C}$
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=30\text{ V}$
				-100		$V_{GS}=-30\text{ V}$
Drain-source leakage current	I_{DSS}			1	A	$V_{DS}=650\text{ V}, V_{GS}=0\text{ V}$

Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C _{iss}		2390.8		pF	V _{GS} =0 V, V _{DS} =50 V, f=100 kHz
Output capacitance	C _{oss}		154.1		pF	
Reverse transfer capacitance	C _{rss}		3.9		pF	
Turn-on delay time	t _{d(on)}		32.4		ns	V _{GS} =10 V, V _{DS} =400 V, R _G =100 Ω, I _D =12.5 A
Rise time	t _r		30.8		ns	
Turn-off delay time	t _{d(off)}		63.2		ns	
Fall time	t _f		4.9		ns	

Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q _g		41.9		nC	V _{GS} =10 V, V _{DS} =400 V, I _D =12.5 A
Gate-source charge	Q _{gs}		10.4		nC	
Gate-drain charge	Q _{gd}		14.1		nC	
Gate plateau voltage	V _{plateau}		5.7		V	

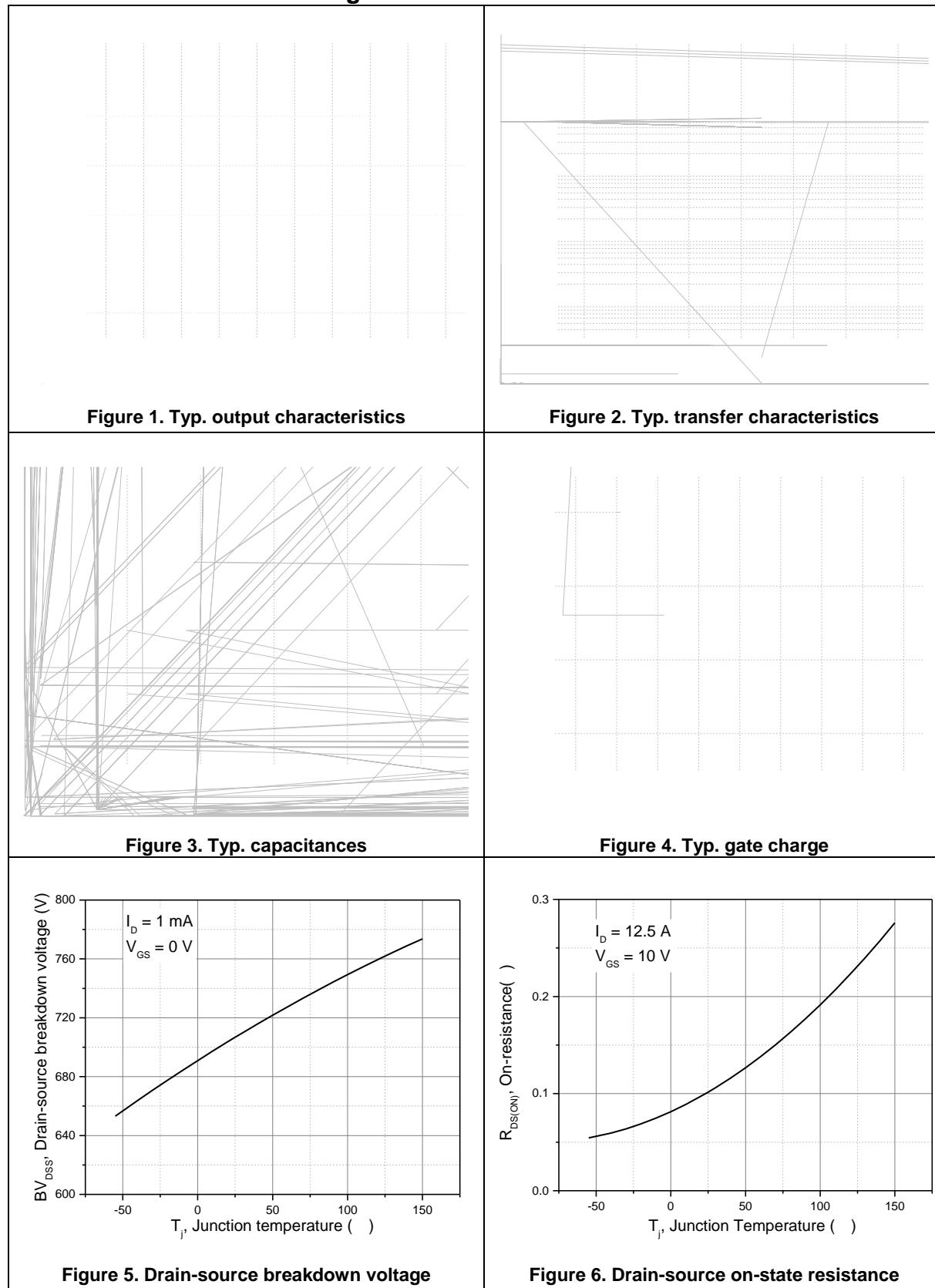
Body Diode Characteristics

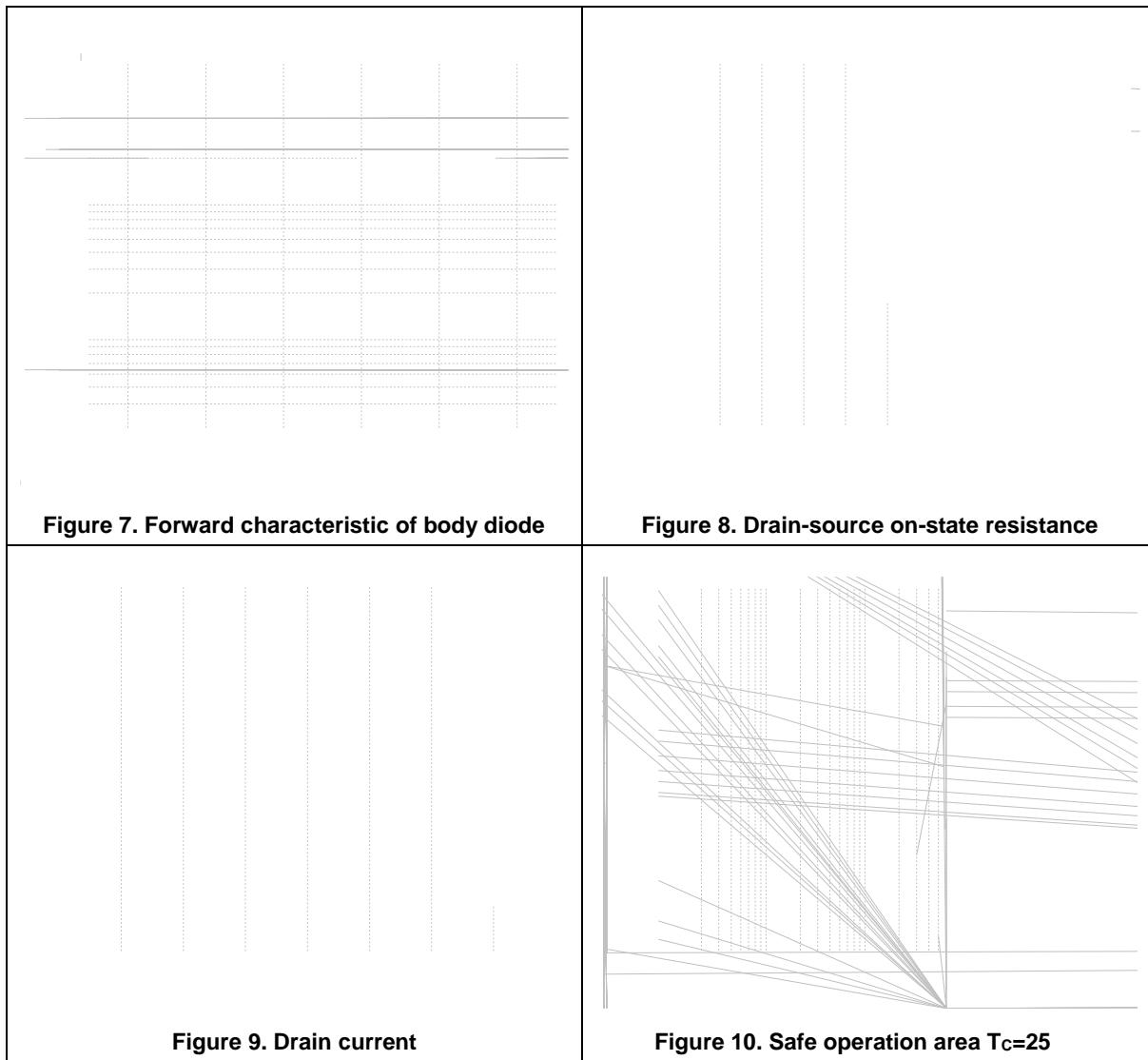
Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward voltage	V _{SD}			1.4	V	I _S =25 A, V _{GS} =0 V
Reverse recovery time	t _{rr}		365.2		ns	I _S =12.5 A, G L G W
Reverse recovery charge	Q _{rr}		4.7		C	
Peak reverse recovery current	I _{rrm}		24.9		A	

Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) Pd is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of R_{DS(on)} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_a=25 °C.
- 5) V_{DD}=100 V, V_{GS}=10 V, L=80 mH, starting T_j=25 °C.

Electrical Characteristics Diagrams





Test circuits and waveforms

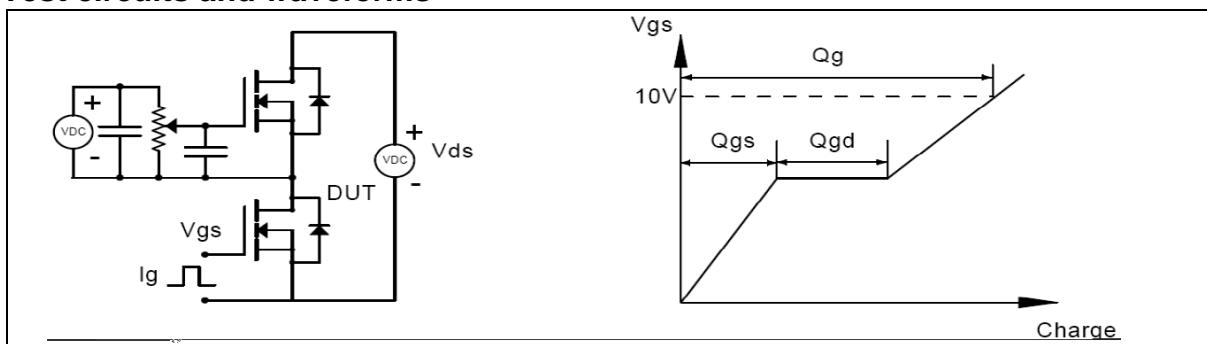


Figure 1. Gate charge test circuit & waveform

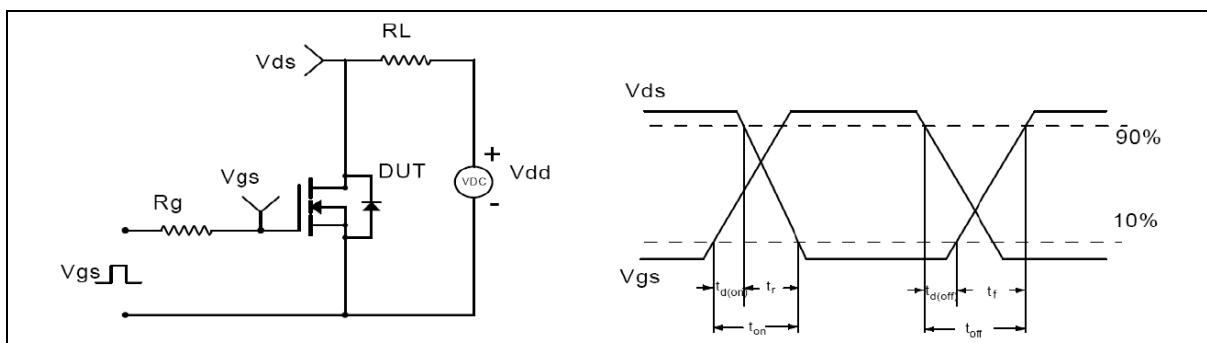


Figure 2. Switching time test circuit & waveforms

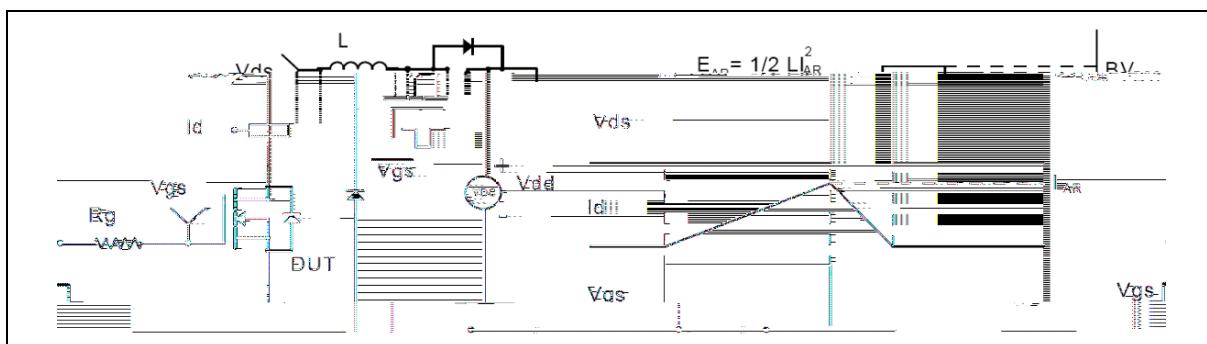


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

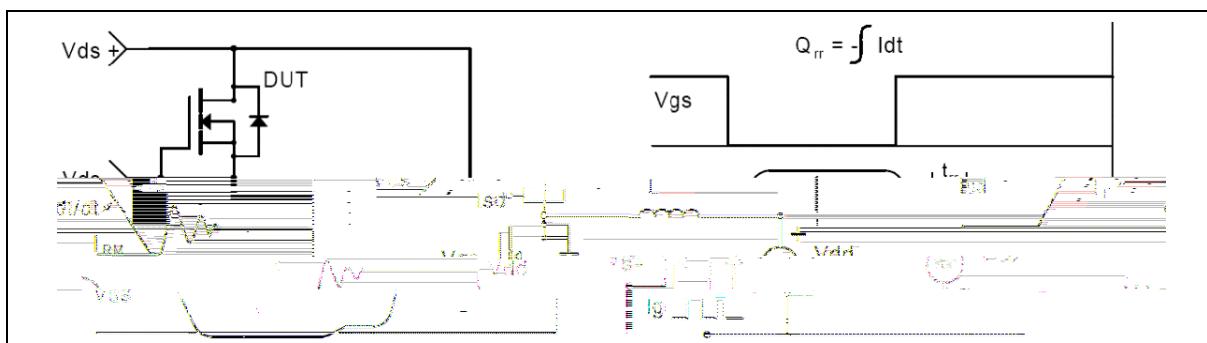


Figure 4. Diode reverse recovery test circuit & waveforms

Package Information

Symbol	mm		
	Min	Nom	Max
A	4.40	4.50	4.60
A1	1.27	1.30	1.33
A2	2.30	2.40	2.50
b	0.70	-	0.90
b1	1.27	-	1.40
c	0.45	0.50	0.60
D	15.30		

Ordering Information

Package Type	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO220-J	50	20	1000	5	5000

Product Information

Product	Package	Pb Free	RoHS	Halogen Free
OSG65R125PF	TO220	yes	yes	yes

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